

# Status of the CSM FPGA Irradiation Test for the HL-LHC ATLAS Muon Spectrometer Upgrade

Jem Guhit, Yuxiang Guo, Xiong Xiao, Xueye Hu, Tom Schwarz

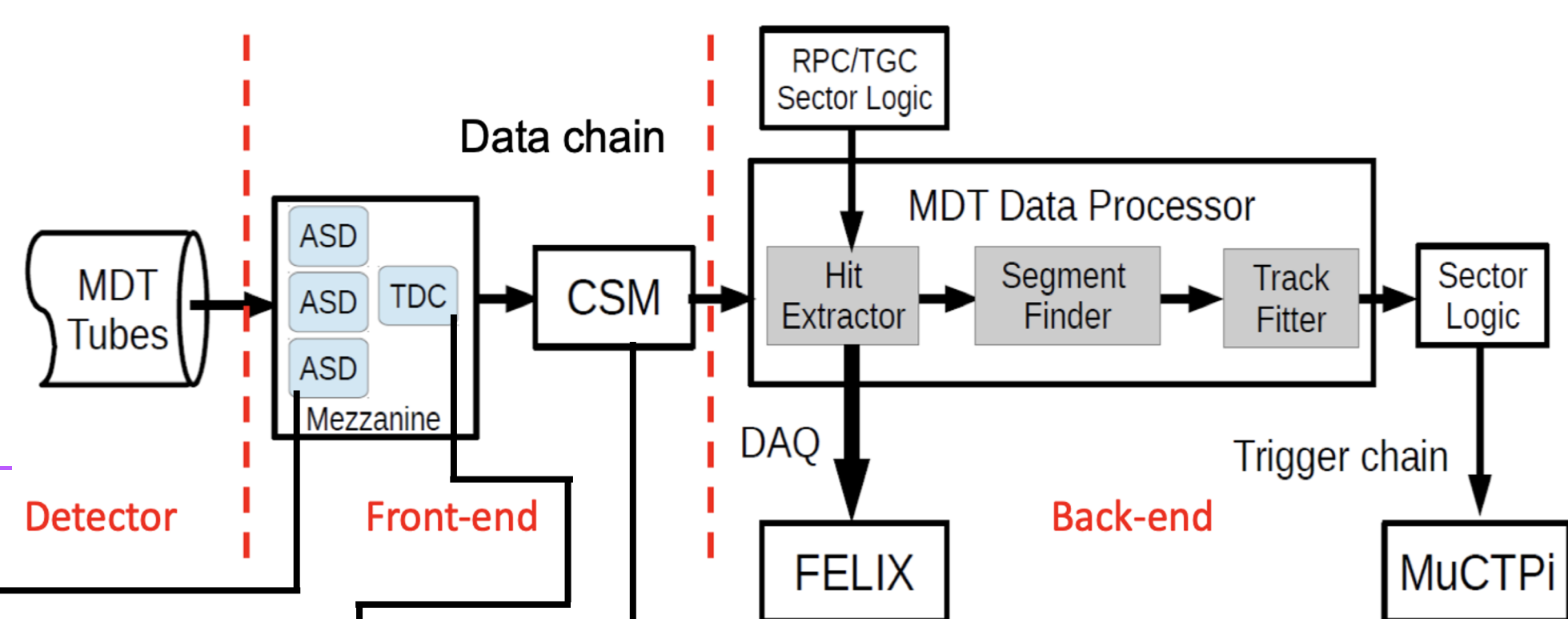
## MDT FRONT END ELECTRONICS

## Block Diagram of MDT Trigger and readout electronics for Phase-II Upgrade

- The upgrade requires **higher trigger rate (1 MHz)** and **longer latency (10  $\mu$ s)**

- New feature:** MDT hits will be included in the level-0 trigger

- Description of **custom-built front-end electronics** below



### ASD (Amplifier- Shaper-Discriminator)

- 3 8-channel, Analog ASIC
- Processes signals from the MDT and sends 8-outputs to TDC
- ASIC designed in MPI-Munich

### TDC (Time-to-Digital)

- Digital ASIC
- Performs a time measurement
- 80 Mbps  $\rightarrow$  320 Mbps x 2
- ASIC designed at the University of Michigan

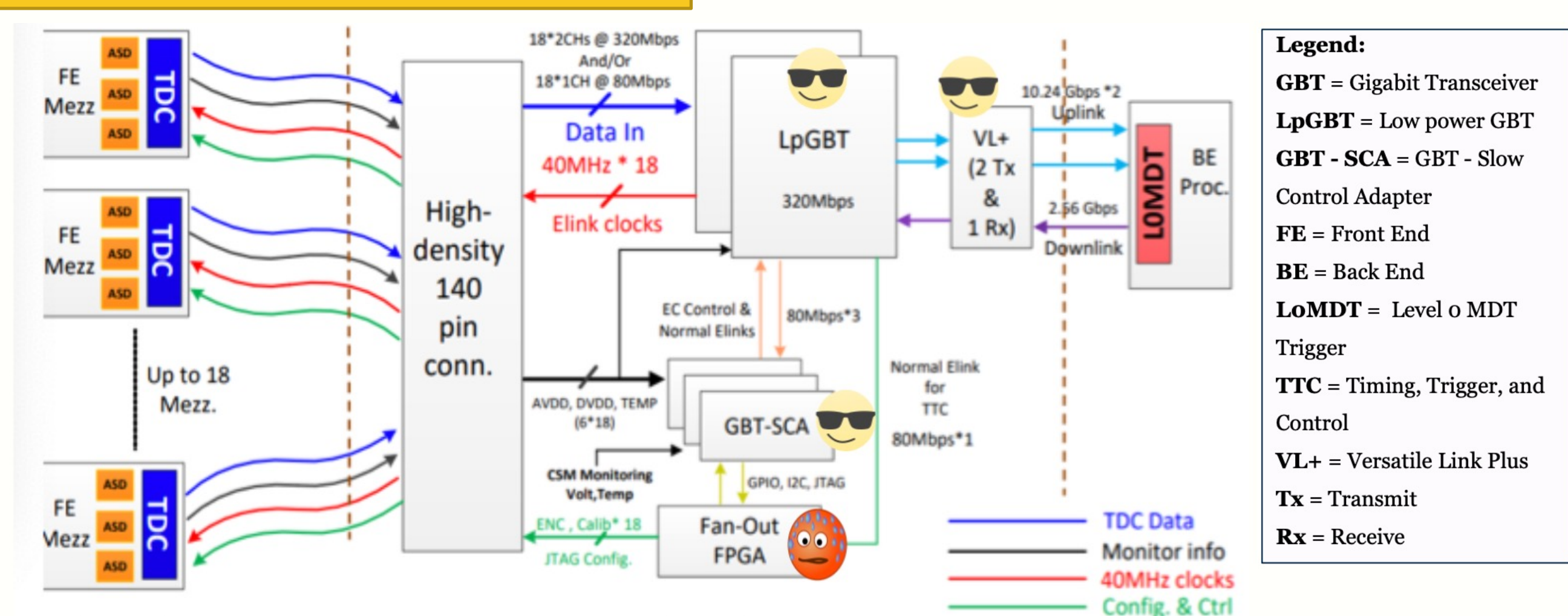
### CSM (Chamber Service Module)

- 20 - Mezzanine Multiplexer board
- LpGBT-based CSM
- 2 Gbps  $\rightarrow$  10.24 Gbps x 2
- CSM designed at the University of Michigan

Talk focuses on testing radiation hardness of a custom-built front-end electronics (mezzanine card + CSM module) for the HL-LHC

arXiv:2011.11699

## Chamber Service Module Logic Flow



### GBT-CSM (Gigabit Transceiver - CSM) Technology:

- Two-fold Function:** a multiplexing center between FE Mezzanines and BE LoMDT and handles TTC and Monitoring information
- LpGBT, GBT-SCA, and VL+ have built-in radiation hardness tested at CERN

Fanout FPGA is the most sensitive component to radiation inside the CSM

## PHASE-II MDT CSM RADIATION REQUIREMENTS

	MDT FE			MDT CSM		
	TID	NIEL	Hadrons>20	TID	NIEL	Hadrons>20
SRL (1000)	15.70	3.57	0.685	5.32	2.91	0.528
4000 fb-1	62.80	14.28	2.74	21.28	11.64	2.11
x(SF sim)	94.20	21.42	4.11	31.92	17.46	3.17
RTC (ASIC)	94.20	27.85	8.22	31.92	22.70	6.34
RTC (COTS)	282.6	83.5	24.7	95.8	68.1	19.0
Max at	BIS8 MDT	BEE	BEE	EIL	EIL	EIL

Figure 1: MDT and RPC Radiation Requirements Radiation based on standard ATLAS simulation

COTS qualification requires no significant performance drop and negligible no. of SEE after an average flux  $1.9E12 \text{ n/cm}^2/10y$

SEE Radiation Requirement

Average Flux in ATLAS per 10 years:  $1.9E12 \text{ n/cm}^2/10y$

Average Flux in ATLAS per seconds:  $6.0E3 \text{ n/cm}^2/s$

## LANSCE IRRADIATION TEST

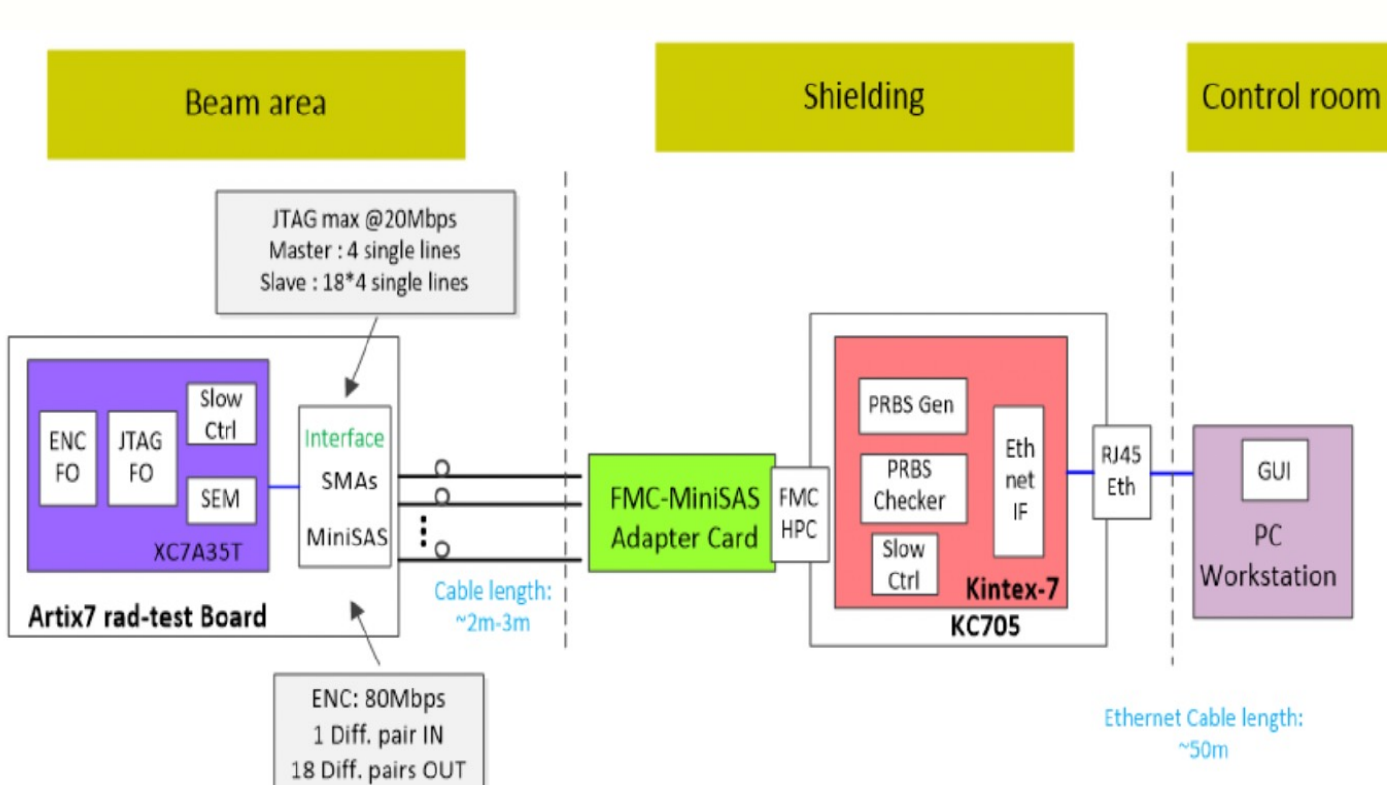
	LANSCE Beam Facility
Neutron Production	Tungsten neutron production target
Beam Energy	Up to 800 MeV
Beam Spectrum	Similar to ATLAS energy spectrum
Beam Size	Collimated 2"
Flight Paths	+/- 30-degrees (ICE-I/ICE-II)
Flux [ $\frac{n}{cm^2 \cdot s}$ ]	$1.54E+06 \cdot \text{Degradation Factors}$
Total Fluence [ $\frac{n}{cm^2}$ ]	$4.72E+11 \cdot \text{Degradation Factors}$

\* > 3 orders of magnitude compared to ATLAS

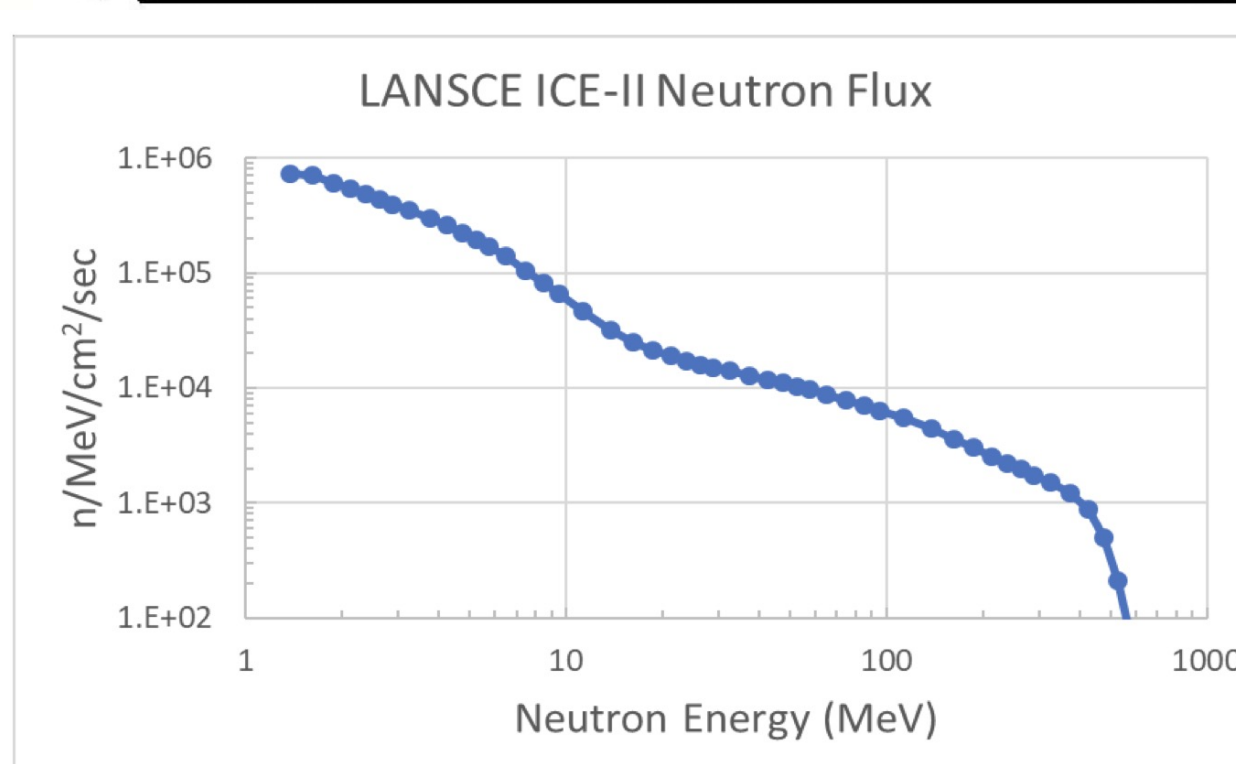
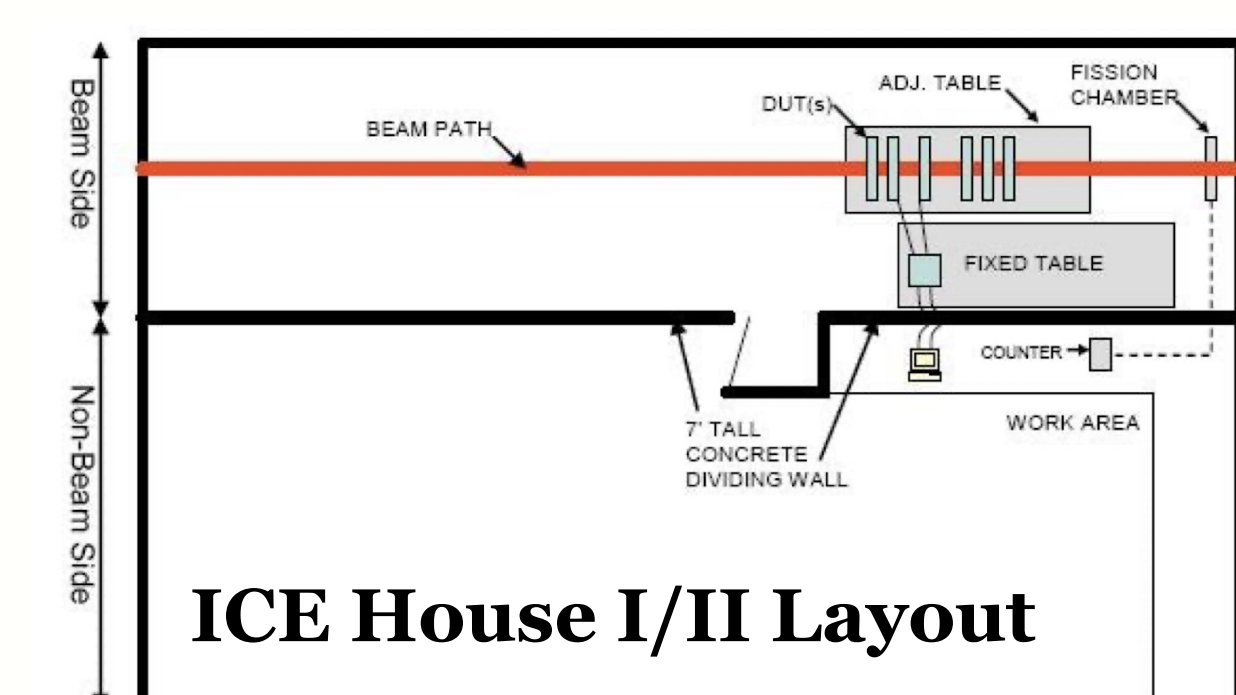
BEAM Degradation Factor:  
CSM Board 1: 0.8970  
CSM Board 2: 0.9080

### Hardware Setup

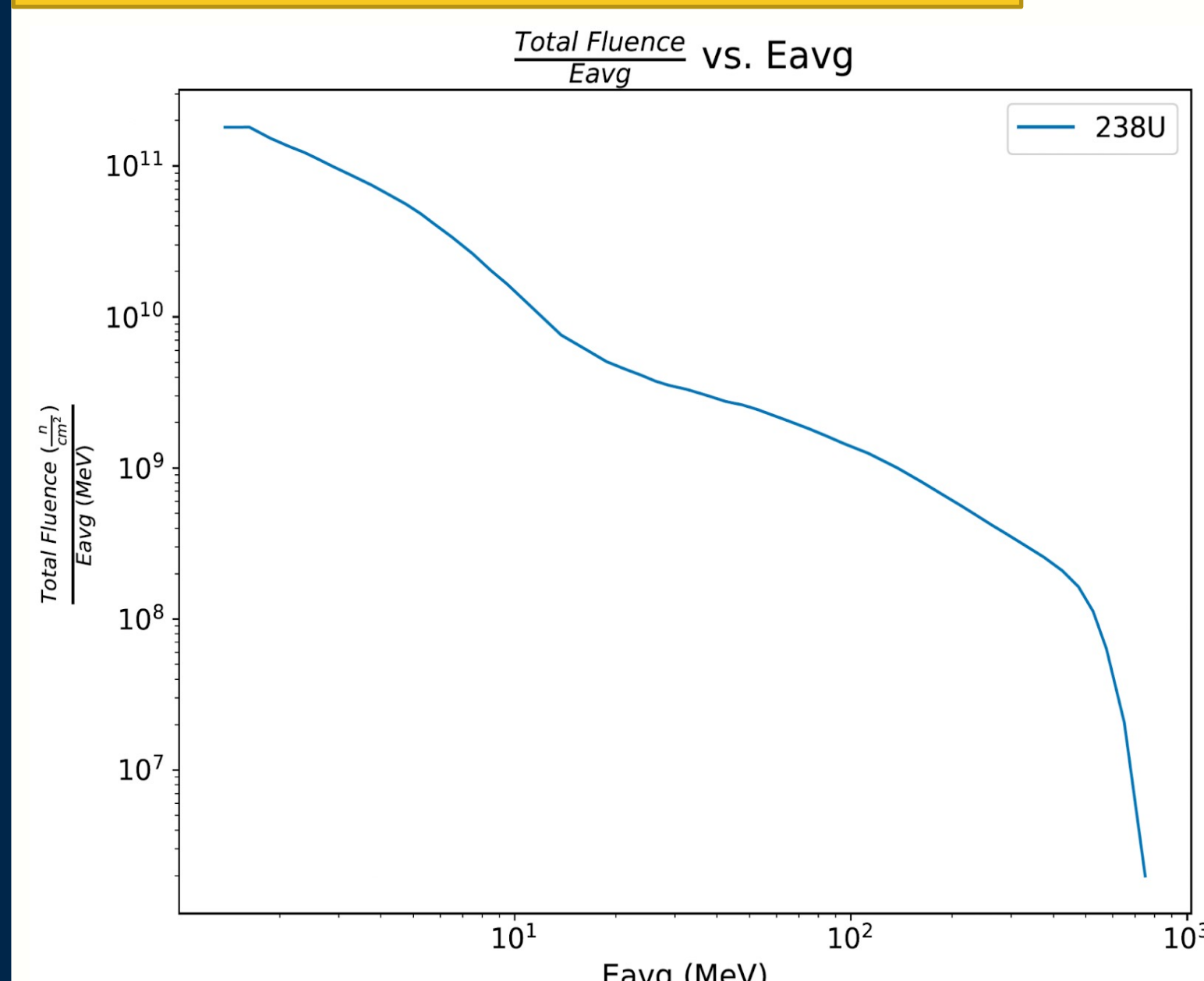
- KC705 Board + Bridge Board + miniSAS cable + Artix-7 rad-test Board
- 2 setups/run with the same hardware, firmware, software



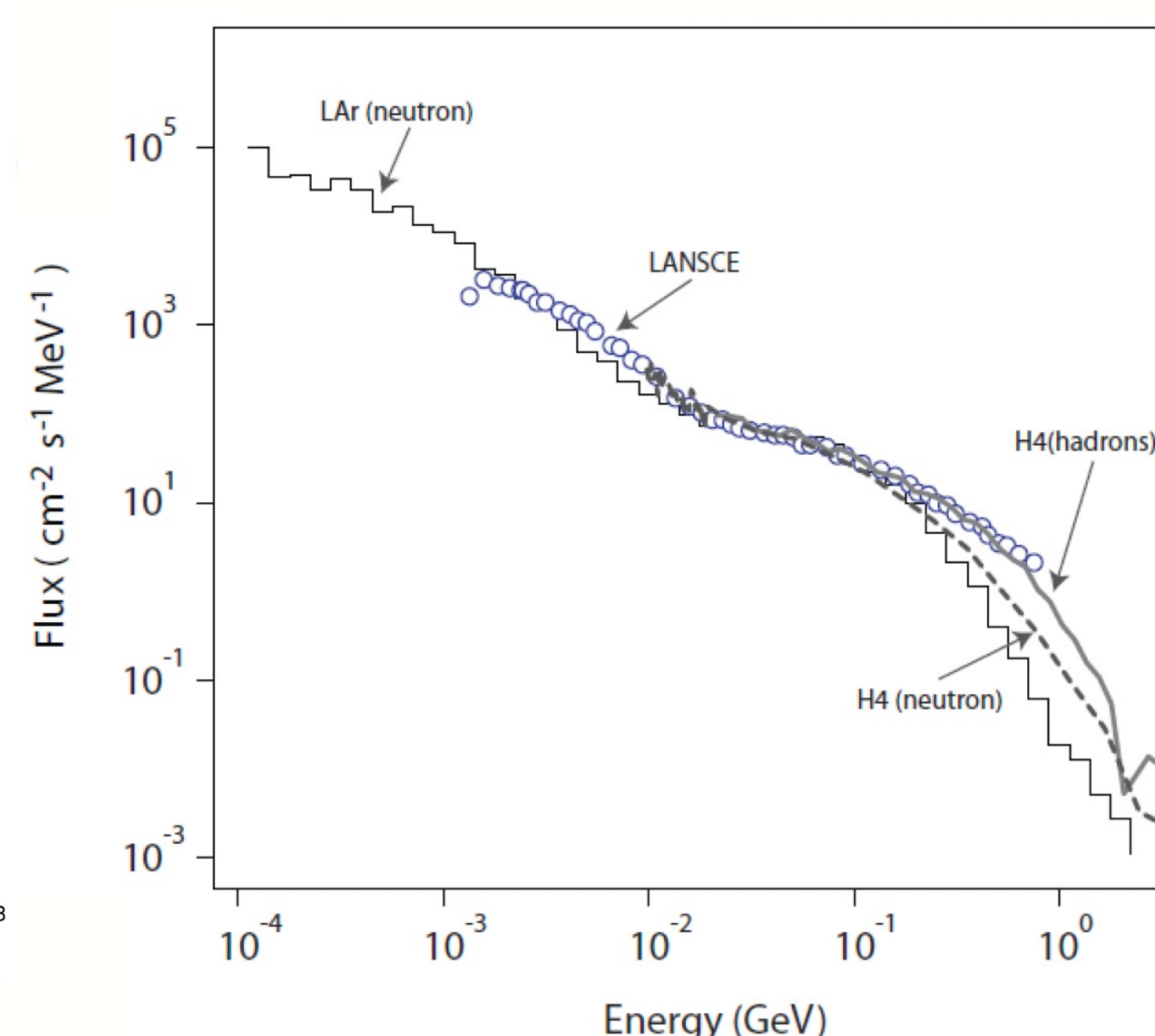
The beam area is the DUT (Artix-7) with a test firmware connected through FMC-miniSAS cables to the DAQ Firmware (KC705) shielded from the beam.



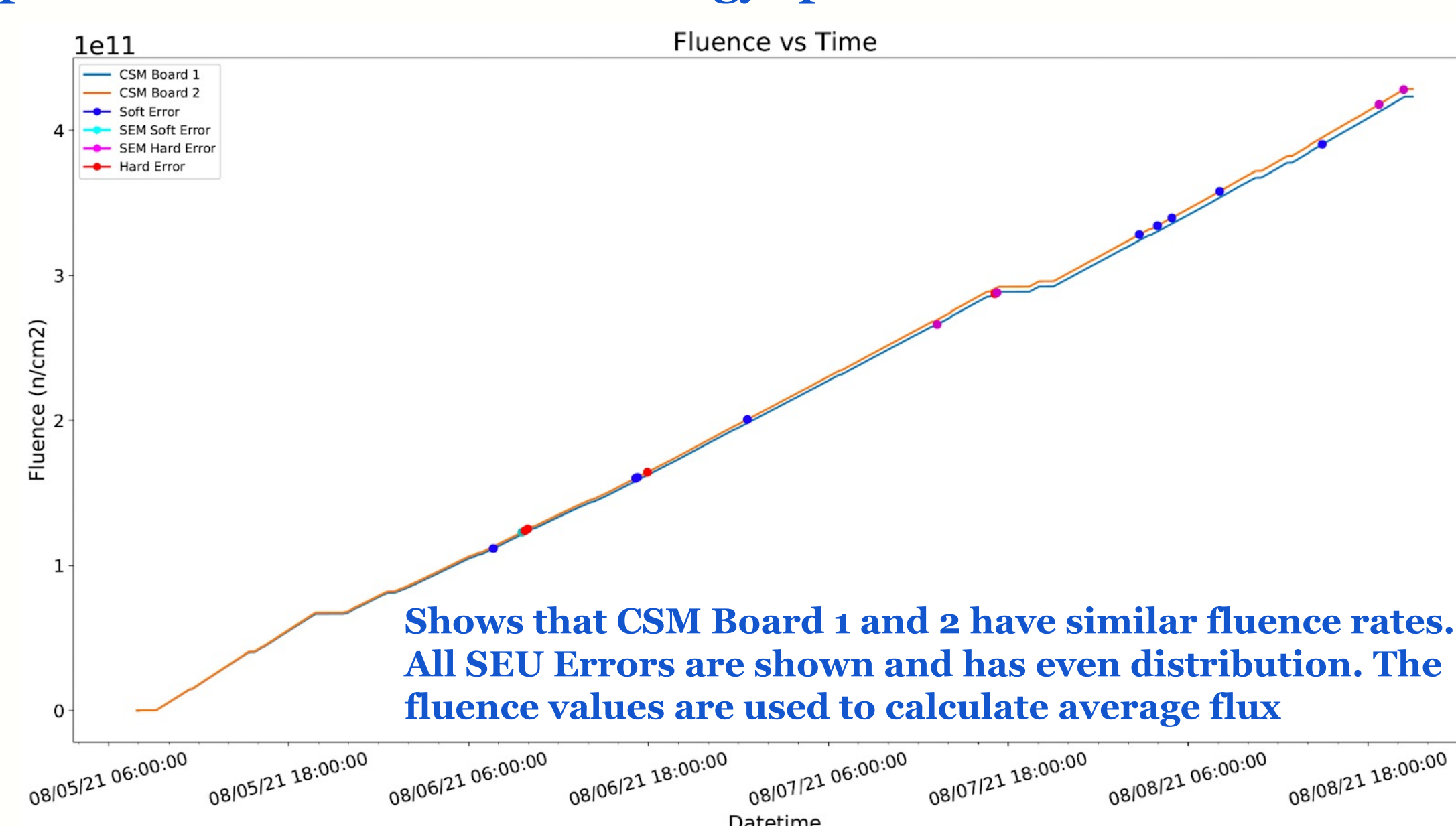
## IRRADIATION TEST RESULTS



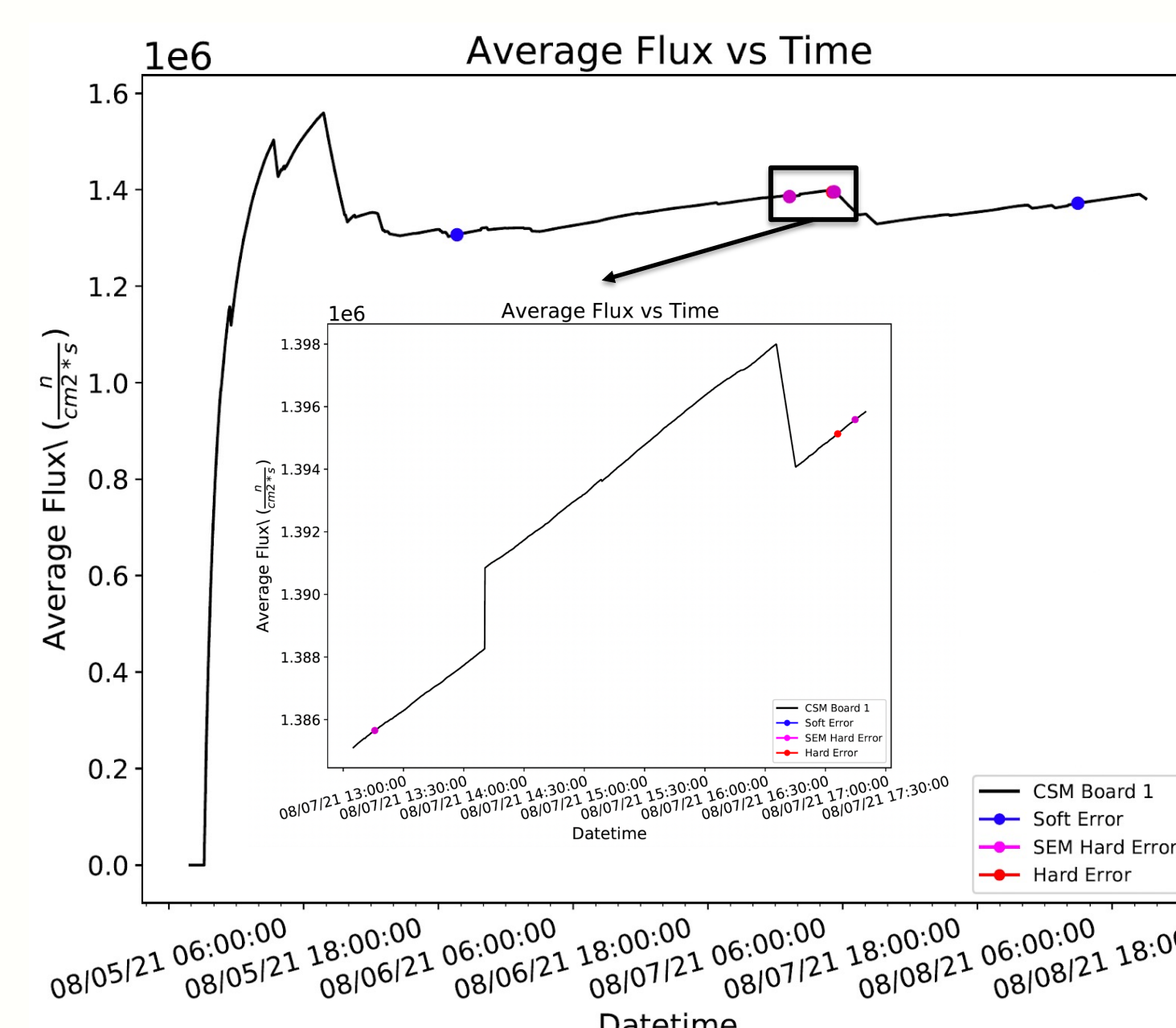
Total Fluence vs Eavg :  
Energy spectrum at LANSCE during Beam run



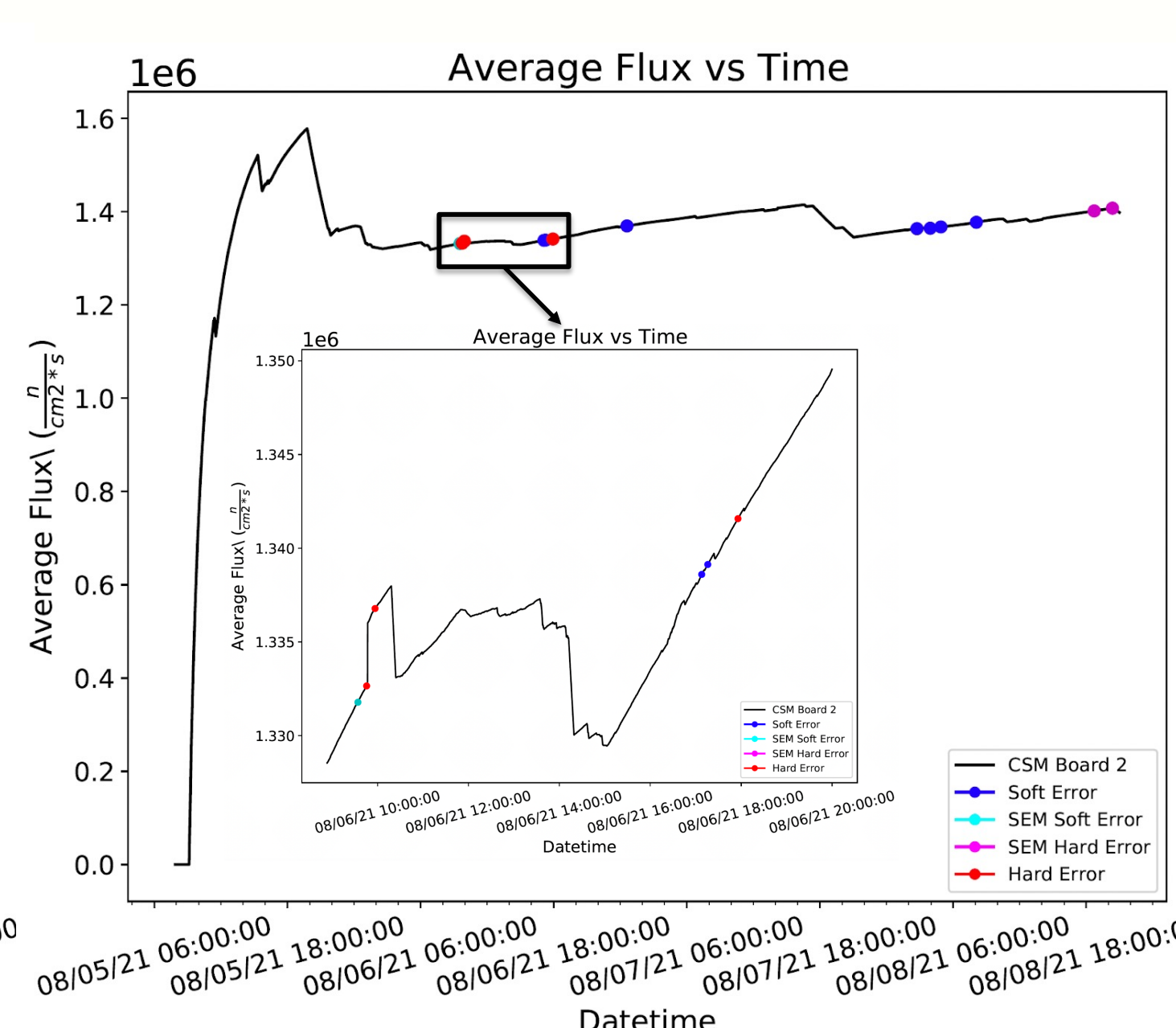
Energy Spectrum of neutrons emitted in fission. A good confirmation that LANSCE Energy Spectrum similar to ATLAS energy spectrum.



Fluence vs Time: Used to calculate Average Flux ( $n/cm^2/s$ )



Average Flux vs. Time: CSM 1 with 5 SEU Errors - 2 Soft Errors, 1 Hard Errors, and 2 SEM Hard Errors (categorized in the end as Hard Errors)



Average Flux vs. Time: CSM 2 with 13 SEU Errors - 7 Soft Errors, 1 SEM Soft Error, 3 Hars Errors, 2 SEM Hard Errors (SEM errors categorized later as either Soft or Hard Error)

CSM Board 1 and 2 also have similar average flux rates. Plots summarize the different SEU errors that occurred during the beam test, and they show optimistic results.

## SUMMARY

	Board #1 Soft Error = 2	Board #1 Hard Error = 3	Board #2 Soft Error = 8	Board #2 Hard Error = 5
Fluence ( $n/cm^2$ )		$4.23E+11$		$4.28E+11$
Ave. Flux ( $n/cm^2/s$ )		$1.33E+06$		$1.34E+06$
Cross-Section ( $cm^2$ )	$4.73E-12 \pm 3.34E-12$	$7.09E-12 \pm 4.09E-12$	$1.87E-11 \pm 6.61E-12$	$1.17E-11 \pm 5.22E-12$
Fluence ( $n/cm^2$ )		$3.55E+11$		$3.59E+11$
Ave. Flux ( $n/cm^2/s$ )		$1.11E+06$ ( $n/cm^2/s$ )		$1.12E+06$
Cross-Section ( $cm^2$ )	$5.63E-12 \pm 3.98E-12$	$8.45E-12 \pm 4.88E-12$	$2.23E-11 \pm 7.88E-12$	$1.39E-11 \pm 6.23E-12$

Table summarizes SEU results. The degradation factors for each board are applied to the fluence, average flux and cross section for soft and hard errors

Good results for custom-built electronics for MDT Phase-II upgrade and pass CSM Radiation Reqs.

## FUTURE WORK

- Successfully conducted SEU Irradiation test at LANSCE using custom-built front-end electronics for the MDT Phase-II upgrade
- Calculate Data Loss %
- Paper in the works to discuss custom-built front-end electronics, Irradiation test, and results
- Total Ionization Dose (TID) Test at BNL concluded and annealing test is ongoing

LANSCE radiation test results are promising, and analysis of SEU Test will continue this year. TID Results to be reported soon.